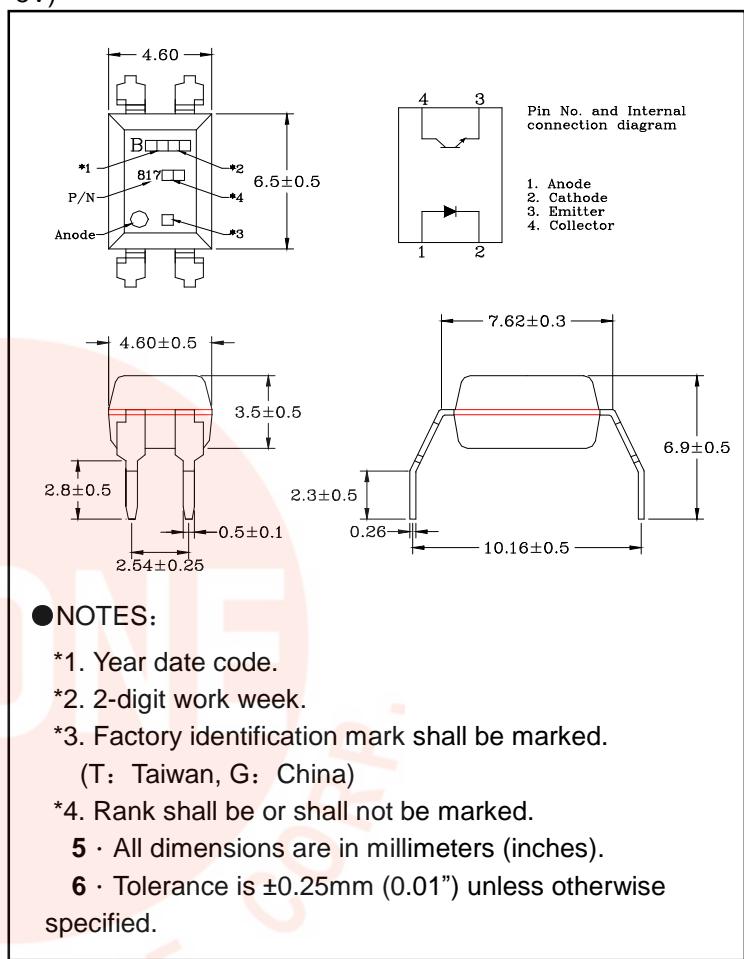




● Features:

1. Current transfer ratio (CTR: MIN. 50% at $I_F=5\text{mA}$, $V_{CE}=5\text{V}$)
2. High input-output isolation voltage ($V_{ISO}=5,000\text{VRms}$)
3. Response time (tr: TYP. 4 μs at $V_{CE}=2\text{V}$, $I_C=2\text{mA}$, $R_L=100\ \Omega$)
4. VDE approved(NO.40007240)
5. UL/CUL approved(NO.E236324)
6. CQC approved(NO.CQC08001026994
NO.CQC05001014257)
7. This product doesn't contain restriction substance, comply RoHS standard

● Outline Dimensions



● NOTES:

- *1. Year date code.
- *2. 2-digit work week.
- *3. Factory identification mark shall be marked.
(T: Taiwan, G: China)
- *4. Rank shall be or shall not be marked.
- 5 · All dimensions are in millimeters (inches).
- 6 · Tolerance is ±0.25mm (0.01") unless otherwise specified.

● Absolute Maximum Ratings (Ta=25°C)

Parameter		Symbol	Rating	Unit
INPUT	Forward Current	I_F	50	mA
	Reverse Voltage	V_R	6	V
	Power Dissipation	P	70	mW
OUTPUT	Collector-Emitter Voltage	V_{CEO}	80	V
	Emitter- Collector Voltage	V_{ECO}	6	
	Collector Current	I_C	50	mA
	Collector Power Dissipation	P_C	150	mW
Total Power Dissipation		P_{tot}	200	mW
*1 Isolation Voltage		V_{iso}	5,000	Vrms
Rated impulse isolation voltage		V_{IOTM}	6,000	V
Rated repetitive peak isolation voltage		V_{IORM}	630	V
Operating Temperature		T_{opr}	-30 to + 110	°C
Storage Temperature		T_{stg}	-55 to + 125	
*2 Soldering Temperature		T_{sol}	260	

*1. AC For 1 minute, R.H. =40~60%

Isolation voltage shall be measured using the following method.

- (1) Short between anode and cathode on the primary side and between collector and emitter on the secondary side.
- (2) The isolation voltage tester with zero-cross circuit shall be used.
- (3) The waveform of applied voltage shall be a sine wave.

*2. For 10 Seconds



● Electro-Optical Characteristics (Ta=25°C)

Parameter		Symbol	Conditions	MIN.	TYP.	MAX.	Unit
INPUT	Forward Voltage	V _F	I _F =20mA	---	1.2	1.4	V
	Reverse Current	I _R	V _R =6V	---	---	10	μA
	Terminal Capacitance	C _t	V=0, f=1KHz	---	30	250	pF
OUTPUT	Collector Dark Current	I _{CEO}	V _{CE} =20V, I _F =0	---	---	100	nA
	Collector-Emitter Breakdown Voltage	BV _{CEO}	I _C =0.1mA I _F =0	80	---	---	V
	Emitter-Collector Breakdown Voltage	BV _{ECO}	I _E =10μA I _F =0	6	---	---	V
TRANSFER CHARACTERISTICS	Collector Current	I _c	I _F =5mA V _{CE} =5V	2.5	---	30	mA
	*1 Current Transfer Ratio	CTR		50	---	600	%
	Collector-Emitter Saturation Voltage	V _{CE(sat)}	I _F =20mA I _C = 1mA	---	0.1	0.2	V
	Isolation Resistance	R _{iso}	DC500V 40~60%R.H.	5×10 ¹⁰	1×10 ¹¹	---	Ω
	Floating Capacitance	C _f	V=0, f=1MHz	---	0.6	1	pF
	Cut-Off Frequency	f _c	V _{CE} =5V, I _C =2mA R _L =100Ω, -3dB	---	80	---	kHz
	Response Time(Rise)	t _r	V _{CE} =2V, I _C =2mA	---	4	18	μs
	Response Time(Fall)	t _f	R _L =100Ω	---	3	18	μs

*1 CTR = I_C / I_F × 100%

● RANK TABLE OF CURRENT TRANSFER RATIO(CTR)

RANK MARK.	Min. (%)	Max. (%)
L	50	100
A	80	160
B	130	260
C	200	400
D	300	600
L or A or B or C or D	50	600

Notes:

*1. Conditions: I_F=5mA, V_{CE}=5V, Ta=25°C.



●CHARACTERISTICS CURVES

Fig.1 Forward Current
vs. Ambient Temperature

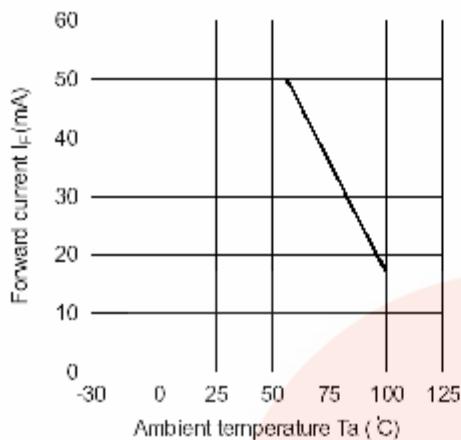


Fig.2 Collector Power Dissipation
vs. Ambient Temperature

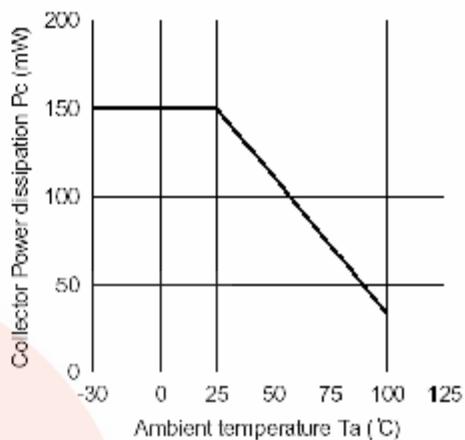


Fig.3 Collector-emitter Saturation
Voltage vs. Forward Current

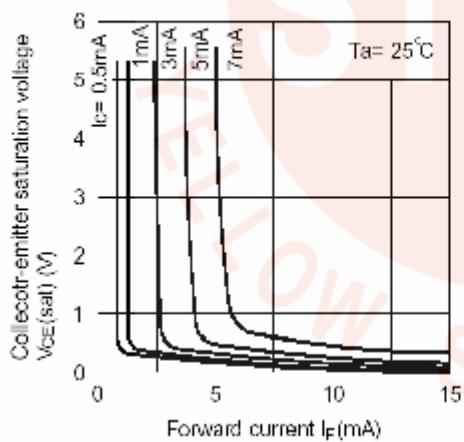


Fig.4 Forward Current vs. Forward
Voltage

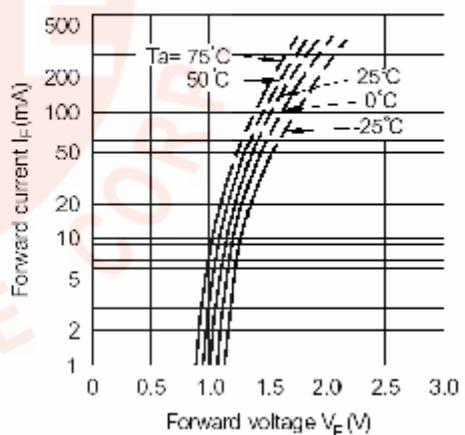


Fig.5 Current Transfer Ratio vs.
Forward Current

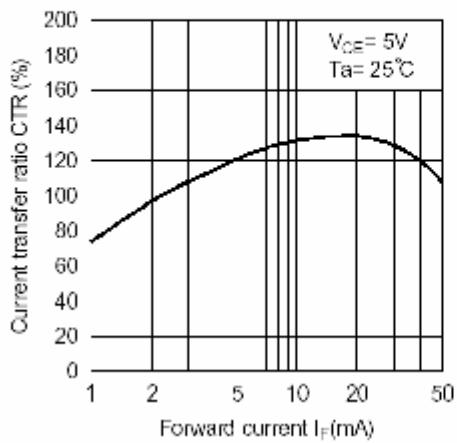
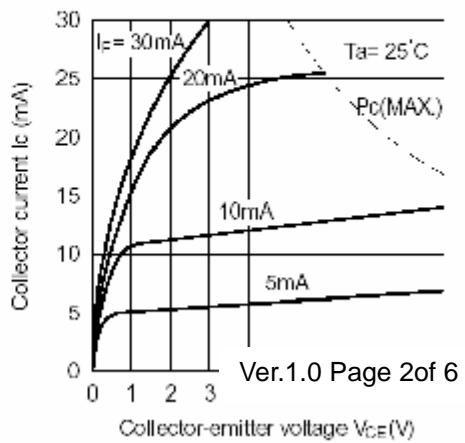


Fig.6 Collector Current vs.
Collector-emitter Voltage





● Characteristics Curves

Fig.7 Relative Current Transfer Ratio vs. Ambient Temperature

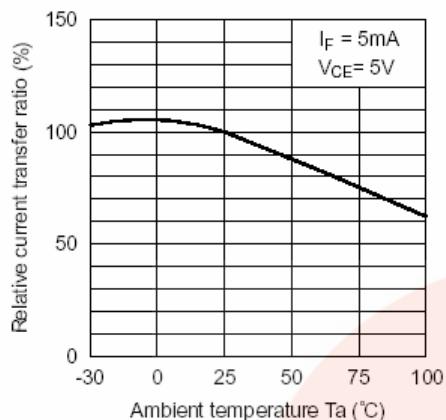


Fig.8 Collector-emitter Saturation Voltage vs. Ambient Temperature

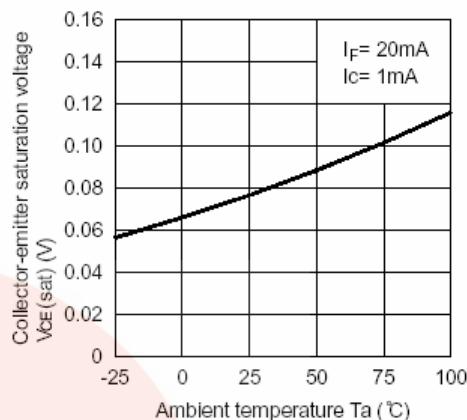


Fig.9 Collector Dark Current vs. Ambient Temperature

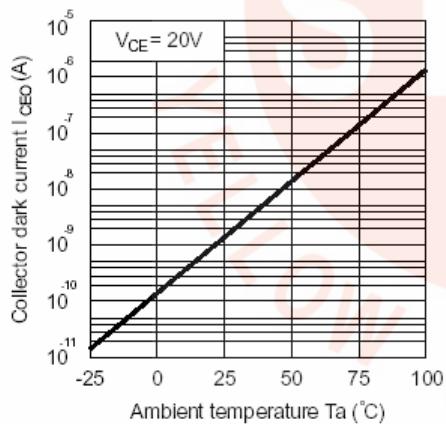


Fig.10 Response Time vs. Load Resistance

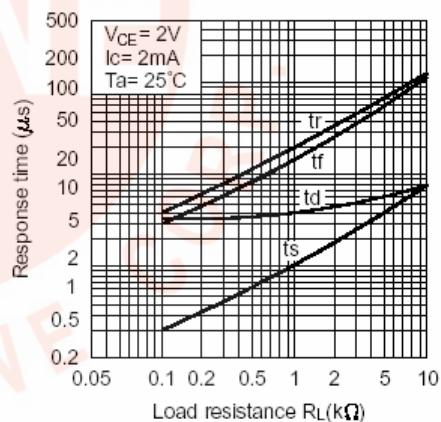
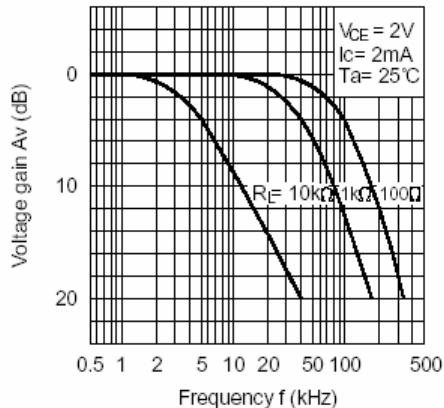
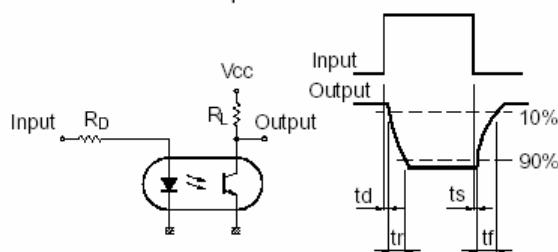


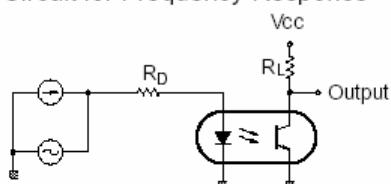
Fig.11 Frequency Response



Test Circuit for Response Time



Test Circuit for Frequency Response



● Reliability Test

Classification	Test Item	Reference Standard	Test Conditions	Result
Endurance Test	Operation Life	MIL-STD-750:1026 MIL-STD-883:1005 JIS C 7021 :B-1	Connect with a power If=50mA Ta=Under room temperature Test time=1,000hrs	0/20
	High Temperature High Humidity Reverse Bias (H3TRB)	JIS C 7021 :B-11	Ta=+85°C±5°C, RH=85% PTR=V _{CE} absolute max rating*80% Test time=1000hrs	0/20
	High Temperature Reverse Bias (HTRB)	JIS C 7021 :B- 8	Ta=+105°C±5°C PTR=V _{CE} absolute max rating Test time=1000hrs	0/20
	High Temperature Storage	MIL-STD-883:1008 JIS C 7021 :B-10	High Ta=+125°C±5°C Test time=1,000hrs	0/20
	Low Temperature Storage	JIS-C-7021 :B-12	Low Ta=-55°C±5°C Test time=1,000hrs	0/20
	Autoclave	JESD 22-A102-B	P=15PSIG, Ta=121°C Humi. =100%RH, 48hrs	0/20
Environmental Test	Temperature Cycling	MIL-STD-202:107D MIL-STD-750:1051 MIL-STD-883:1010 JIS C 7021 :A-4	125°C ~ 25°C ~ -55°C ~ 25°C 30min 5min 30min 5min Test Time=20cycle	0/20
	Thermal Shock	MIL-STD-202:107D MIL-STD-750:1051 MIL-STD-883:1011	125°C ~-55°C 20min 20min Test Time=20cycle	0/20
	Solder Resistance	MIL-STD-202:201A MIL-STD-750:2031 JIS C 7021 :A-1	Operation heating : 260°C, within 10±1seconds.	0/20
	Solder Ability	MIL-S-883:2003 JIS C 7021 :A-2	Operation heating : 235°C, within 5±1seconds.	0/20

● Judgment Criteria Of Failure For The Reliability

Symbol	Measuring conditions	Judgment criteria for failure
V _F (V)	If=20mA	Over Ux1.0
I _r (uA)	V _r =6V	Over Ux1.0
CTR(%)	If=5mA, V _{CE} =5V	Shift>1.2
V _{CE(sat)}	I _F =20mA, I _C = 1mA	Over Ux1.0
BV _{CEO}	I _C =0.1mA, I _F =0	Over Lx1.0
BV _{ECO}	I _E =10μA, I _F =0	Over Lx1.0